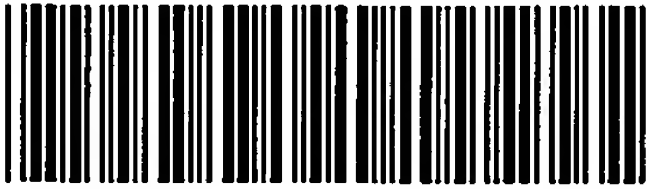


Search Notes



Application/Control No.

10/026,618

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

LEE ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	316	6/5/06	EB
	326		
	327		
	340		
	341		
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	344		
375	345	6/5/06	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EB ASI	6/5/06	EB